## Issue Classification



Application/Control N	10
-----------------------	----

10700124

FRAHM ET AL.

Applicant(s)/Patent Under Reexamination

Examiner

Art Unit

Lee, Siu M

2611

ORIGINAL							INTERNATIONAL CLASSIFICATION								
CLASS SI				SUBCLA	UBCLASS			CLAIMED						ION-CL	AIMED
375			350			н	0	4	В	1 / 10 (2006.01	.01)	ļ			-
	С	ROSS RE	FERENCE	E(S)					•		$\dashv$	<u> </u>	ļ		
CLASS	su	BCLASS (O	NE SUBCLA	SS PER E	BLOCK)	1									
375	279	295	350	229	301										
348	608	722	723	724	470										
				_		-	<u> </u>	<u> </u>				-	ļ		
				_		-	-	<u> </u>				╂	<u> </u>	$\vdash$	
						+		-				+	-		
					-	_		_			+	+		<del>                                     </del>	
		<del></del>	-			+						+			
	1					$\top$	1					1			
		ļ		ļ								1	_		
							_	ļ				<u>                                     </u>	<u> </u>		
	<u> </u>						ļ	ļ		·			<del> </del>		
	ļ	+	+				<del> </del>				_	- <del> </del>			
	<u> </u>	+			-		╁		-		<del></del>	+	╁		
						+		,				+	$\vdash$		
		•					<del>                                     </del>								
				,											
							<u> </u>						_		
							<u> </u>	ļ				<del> </del>	_		
·				_			ļ						ļ		
	•					+	$\vdash$	$\vdash$	-		_	╁	├		
				-			$\vdash$	<del>                                     </del>	$\vdash$				-		
						╁	-								
						_	<b>†</b>					1	$\vdash$		
,															
ee, Siu M	Examiner)		0/20/2007 Date)		Chi	Į,	ان	へ	)	$\mathcal{V}$		Tot	al C	aims A	llowed:
(Legal Histruments (Date)				(Prin	CHIEH M. FAN SUPERVISORY PATENT EXAMINER (Primary Examiner)						O.G. Print Claim(s)			O.G. Print Figur	